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**EMC performance equivalence measurement
of semiconductors**

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Foreword

This standard was developed by the Semiconductor EMC Subcommittee of the Semiconductor System Solution Technical Committee of the Semiconductor Standardization Expert Committee of the Japan Electronics and Information Technology Industries Association (**JEITA**), and was established after deliberation by the same committee. This standard is an individual standard developed according to the format of **JEITA TSC-16** (Japan Electronics and Information Technology Industries Association, Standards Development Standards), and was developed in consideration of evaluating the EMC performance of individual semiconductor products when process changes (PCN: Process Change Notice) occur in semiconductor products. This standard is a copyrighted work protected by copyright law, and may not be reproduced or duplicated in whole or in part without permission. This standard is established without regard to the possibility that any part of this standard may conflict with industrial property rights (patent rights, utility model rights, design rights, etc.). Japan Electronics and Information Technology Industries Association (**JEITA**) shall not be responsible for checking such industrial property rights.